

Notice of References Cited	Application/Control No. 09/808,067	Applicant(s)/Patent Under Reexamination ABBOTT ET AL.	
	Examiner Scott L. Jarrett	Art Unit 3623	Page 1 of 3

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	Examiner Scott L. Jarrett	Art Unit 3623	Page 2 of 3

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	Examiner Scott L. Jarrett	Art Unit 3623	Page 3 of 3

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